Search Notes

Application/Control No.	pplicant(s)/Patent under leexamination	
10/053,431	CHUNG ET AL.	
Examiner	Art Unit	
Hau H. Nguyen	2676	

		CUED			
	SEARCHED				
Class	Subclass	Date	Examiner		
345	501, 506, 542, 552, 553, 557	3/2/2006	HN		
712	2,7,13	3/2/2006	HN		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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